Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/724,789	FUTOHASHI, ICHIRO	
Examiner	Art Unit	
Richard Chan	2685	

	SEARCHED				
Class	Subclass	Date	Examiner		
379	375	3/14/2006	RC		
379	373	3/14/2006	RC		
455	567	3/14/2006	RC		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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DATE	EV. 45
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